Volume 3, No.4, April 2014

International Journal of Advances in Computer Science and Technology Available Online at http://warse.org/pdfs/2014/ijacst09342014.pdf

PERFORMANCE ANALYSIS OF PRIORITIZED TEST SUITES BASED ON FAULT DETECTION



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ABSTRACT

Specification based testing identifies test cases from software requirement specifications. This leads to better quality software which reduces effort and cost. Test cases generated for Boolean specifications have been widely used to specify requirements of safety critical softwares, avionics, medical and other control software. Various Boolean specification techniques have been proposed among them MC/DC and MUMCUT techniques are the popular testing techniques. Compliance of the MC/DC criterion has been mandated by Federal Aviation Administration for the approval of airborne software. According to Kaminski (2010) the Federal Aviation Administration requires the Minimal-MUMCUT criterion instead of MC/DC for Irredundant Disjunctive Normal Form (IDNF). The Minimal-MUMCUT criterion provides better logic fault detection .In this paper performance analysis of proposed prioritized test suite generated from Minimal MUMCUT has been done. The APFD of prioritized test suite is computed and compared with other possible prioritized test suites. Minimal MUMCUT identified testing techniques for Boolean specification for which various 2ⁿ distinct Boolean functions with n variables can be formed. To distinguish one from all others using exhaustive testing, it would require 2ⁿ distinct test cases. Test cases generated by Minimal MUMCUT are less than the test cases generated by MUMCUT Strategy. The proposed approach for prioritization of test cases generated by Minimal MUMCUT yields higher APFD and hence early detection of faults.

Key words: MUMCUT, MUTP, CUTPNFP, APFD

1. INTRODUCTION

Software testing and retesting occurs continuously during the software development life cycle to detect errors as early as possible. During the regression testing, a modified system needs to be retested using the existing test suite. Since the test suite may be very large, the better way is to prioritize it. Regression testing is a necessary but expensive process in the software lifecycle. One of the regression testing approaches, test case prioritization, aims at sorting and executing test case in order of potential abilities to achieve certain testing objective. Test Case Prioritization [8] schedule test cases for regression testing in an order that attempts to maximize some objective function. For example, testers might wish to schedule test cases in an order that achieves code coverage at the fastest rate possible, exercises features in order of expected frequency of use, or exercises sub-systems in an

order that reflects their historical propensity to fail. When the time required to execute all test cases in a test suite is short, test case prioritization may not be cost effective, it may be most expedient simply to schedule test cases in any order. In the past decade, may testing criteria have been proposed for software characterized by complex logical decisions, such as those in safety-critical software[1],[2].[3]. In recent years, more sophisticated coverage criteria have been advocated, like BOR (Boolean OpeRator Testing Strategy), BMIS (Basic Meaningful Impact Strategy), modified condition/decision coverage (MC/DC) ([1] [2] [4]) and the MUMCUT criteria. [5]

MUMCUT strategy is to generate test cases that can guarantee detection of seven types of single faults provided that the original expression is in irredundant disjunctive normal form (IDNF) [6]. In this strategy, there is no restriction on the number and occurrence of variables in the given Boolean expressions. Minimal-MUMCUT [7] that improves the MUMCUT strategy by considering the feasibility problem of the three testing constituents of the MUMCUT strategy, It reduces the test suite size as compared to MUMCUT without compromising any fault detection capability. Thus, the extra tests required by the MUMCUT criterion are of little, if any, value based on the theoretical and empirical studies conducted [7].

2. TEST CASE PRIORITIZATION

Test case prioritization techniques schedule test cases in an execution order according to some criterion. Test case prioritization problem is defined [8] as follows:

Given: T, a test suite; PT, the set of permutations of T; f, a function from PT to the real numbers

Problem: Find T' belongs to PT such that (for all T") (T" belongs to PT) $(T" \neq T') [f(T') \geq f(T")]$

Here, PT represents the set of all possible prioritizations (orderings) of T and f is a function that, applied to any such ordering, yields an award value for that ordering. The performance of the prioritization technique used is known as effectiveness. It is necessary to assess effectiveness of the ordering of the test suite. Effectiveness will be measured by the rate of faults detected. The following metric is used to calculate the level of effectiveness:

2.1 Average Percentage of Faults Detected (APFD) Metric

APFD (Average Percentage Fault Detected) metric is a measure of how rapidly a prioritized test suite detects faults,

which measures the weighted average of percentage of faults detected over the life of a test suite. [9], [8]. The APFD used in this paper is calculated by taking the weighted average of the number of faults detected during the run of the test suite. APFD can be calculated using the following notations:

Let T - The test suite under evaluation

m - The number of faults contained in the program under test P

n - The total number of test cases and

TFi - The position of the first test in T that exposes fault i. $APFD = 1 - \frac{TF1 + TF2 + TF3 + TF4 + TF5 - \dots - TFi}{m + n} + \frac{1}{2 + n}$

APFD can be calculated when prior knowledge of faults is available. APFD values ranges from 0 to 100; higher value implies faster (better) fault detection rates.

3. FAULT BASED PRIORITIZATION OF MINIMAL MUMCUT TESTS

Single faults of seven types mentioned in Section 4.1, are generated using JAVA eclipse and JAVA collection framework. For the given expression Minimal MUMCUT test cases are generated and a feasibility criterion is tested. Test cases are arranged according to the algorithm for fault based prioritization of Minimal MUMCUT test cases. Algorithm is given below:

Input: Test suite T and number of faults detected by a test case

Output: Prioritized Test suite T'.

- 1. Begin
- 2. Set T' empty
- 3. For each term X do
- 4. If MUTP criteria is feasible for X

Prioritize Multiple Unique True Points (U) followed by overlapping Near False Points (N)

- 5. for each literal x in term X
- 6. If CUTPNFP criteria is feasible for x

Prioritize Unique True Points (U) followed by Corresponding Unique True Points Near False Points(C)

- 7. End for
- 8. Else

Prioritize Multiple Unique True Points (U) followed by Corresponding Unique True Points Near False Points(C) followed by overlapping Near False Points (N)

- 9. End For
- 10. End

4. PROPOSED WORK

4.1 Faults in Logical Expressions

A fault is an error in the original Boolean expression. A faulty implementation is referred to as single-fault expression if (1) it differs from the original expression by one syntactic change; and (2) it is not equivalent to the original expression. This study considers the following classes of simple faults for logical decisions. A decision *S* in *n* variables can always be

written in *disjunctive normal form* (DNF) as a sum of product (Lau, Yu [2001]).

$$S=ab + \overline{c}d + e$$

Table1: Types of Faults

Fault	Description	Example		
Expressio	The expression or	$\frac{\overline{ab} + \overline{c}d}{ab + \overline{c}d} + e$		
n Negation	sub-expression is			
Fault (ENF)	negated			
Term	A term is negated	$\overline{ab} + \overline{c}d + e$		
Negation				
Fault (TNF)				
Term	A term is omitted	$\overline{cd} + e$		
Omission				
Fault (TOF)				
Operator	An OR operator(+)	$ab.\overline{c}d + e$ or		
Reference	is implemented as the	$a + b + \overline{c}d + e$		
Fault (ORF)	AND operator or vice			
	versa			
Literal	A literal is negated	$\overline{a}b + \overline{c}d + e$		
Negation				
Fault (LNF)				
Literal	A literal is omitted	$b + \overline{c}d + e$		
Omission				
Fault (LOF)				
Literal	A literal is inserted	$abc + \overline{c}d + e$		
Insertion				
Fault (LIF)				
Literal	A literal is	$\overline{ac} + \overline{c}d + e$		
Reference	implemented as			
Fault (LRF)	another literal			

4.2 Fault Generation

Fault generation is handled by a series of complex string manipulations on JAVA Eclipse using JAVA Collection Frameworks. The general methodology of generating faults starts with the expression, which is just an infix string at this point, being passed through a tokenizer. The tokens then are searched for the one that will have the fault inserted before or after.

Input: All the single faults take the original Boolean expression in IDNF form

Output: Give all the faulty expressions as output

4.2.1 Operator Negation Fault (ONF)

Step1: Count the number of operators in the expression. This number indicates how many derivatives will be created from this one expression and allows the allocation of storage for each result.

Step 2: From this point onwards, the string is tokenized and the tokens are copied to each of the resulting expressions.

Step 3: Do until all tokens have processed

(a) If the token is an AND operator (&) in the Boolean expression then it is replaced by the OR (|) operator and vice versa.

- (b) If the token is an OR operator (/) in the
- (c) the AND (&) operator and vice versa.

Step 4: With this process complete, the program returns the resulting array of faulty string expressions.

4.2.2 Expression Negation Fault (ENF):

Step 1: Insert a negation before each "opening parenthesis."

Step 2: The program recursively searches for groups of operands that are joined via an "and" operator, these groups can include other scoped parts of the expression or the entire expression itself.

Step 3: Each of the "& blocks" are surrounded by parenthesis and then the entire "and block" is negated.

Step 4: The resulting data is optimized into an array with no empty spaces and the program returns the resulting array of faulty string expressions.

4.2.3 Variable Negation Fault (VNF)

Step 1: Count the number of variable in the expression. This number indicates how many derivatives will be created from this one expression and allows the allocation of storage for each result.

Step 2: From this point onwards, the string is tokenized and the tokens are copied to each of the resulting expressions.

Step 3: Do until all tokens have processed

- (a) If the token is a variable, then a negation operator(!) is inserted
- (b) If the token is a negated variable, then the negation operator is removed

Step 4: With this process complete, the program returns the resulting array of faulty string expressions.

4.2.4 Term Negation Fault (TNF):

Step 1: Count the number of terms in the expression. This number indicates how many derivatives will be created from this one expression and allows the allocation of storage for each result.

Step 2: From this point onwards, the string is tokenized and the tokens are copied to each of the resulting expressions.

Step 3: Do until all tokens have processed

- a) If the token is a term, then a negation operator (!) is inserted
- b) If the token is a negated term, then negation operator is removed

Step 4: With this process complete, the program returns the resulting array of faulty string expressions.

4.2.5 Term Omission Fault (TOF)

Step 1: Count the number of terms in the expression. This number indicates how many derivatives will be created from this one expression and allows the allocation of storage for each result

Step 2: From this point onwards, the string is tokenized and the tokens are copied to each of the resulting expressions.

Step 3: Do until all tokens have processed

Boolean expression then it is replaced by

(a) If the token is a term, then term is omitted

Step 4: With this process complete, the program returns the resulting array of faulty string expressions.

4.2.6 Literal Omission Fault (LOF)

Step 1: Count the number of literals in the expression. This number indicates how many derivatives will be created from this one expression and allows the allocation of storage for each result.

Step 2: From this point onwards, the string is tokenized and the tokens are copied to each of the resulting expressions.

Step 3: Do until all tokens have processed

(a) If the token is a literal, then that literal is omitted

Step 4: With this process complete, the program returns the resulting array of faulty string expressions.

4.2.7 Literal Insertion Fault (LIF)

Step 1: Count the number of literals in the expression. This number indicates how many derivatives will be created from this one expression and allows the allocation of storage for each result.

Step 2: From this point onwards, the string is tokenized and the tokens are copied to each of the resulting expressions.

Step 3: Do until all tokens have processed

(a) If the token is a term, then a literal (which is not present in that term) is inserted before that same token

Step 4: With this process complete, the program returns the resulting array of faulty string expressions.

4.2.8 Variable Reference Fault (VRF)

Step 1: Count the number of literals in the expression. This number indicates how many derivatives will be created from this one expression and allows the allocation of storage for each result.

Step 2: From this point onwards, the string is tokenized and the tokens are copied to each of the resulting expressions.

Step 3: Do until all tokens have processed

a) If the token is a literal, then this literal is replaced by all the other literals present in the expression

Step 4: With this process complete, the program returns the resulting array of faulty string expressions.

4.3 Total Number of Faults of Various Types for TCAS Boolean Expressions

Total number of faults of types ONF, TNF, TOF, LIF, LOF, ENF, VRF, and VNF are generated for TCAS Boolean expressions and a subset of some Boolean expressions. The result is tabulated in Table 2. According to these results the total number of generated faults is 9087 for TCAS 20 Boolean expressions with a subset of some Boolean expressions and for one expression value of single faults ranges from 52 to 1470.

Table2: Number of Generated Faults

S.	EXPRESSION	ONF	ENF	LIF	LOF	TNF	TOF	VNF	VRF	Total
N.	TO1	20	5		20	_	-	20	174	201
1	T01	28	- C	6	29	5	5	29	174	281
2	T02	105	13	12	106	13	13	106	848	1216
3	T04	6	3	8	7	3	3	7	28	65
4	T05	27	9	53	28	9	9	28	224	387
5	T06	57	6	8	58	6	6	58	580	779
6	T08	31	4	-	32	4	4	32	224	331
7	T09	13	1	-	14	2	2	14	84	130
8	T10	59	6	18	60	6	6	60	720	935
9	T11	62	9	54	63	9	9	63	756	1025
10	T12	-	-	-	-	-	-	-	-	-
11	T13	13	6	58	14	6	6	14	154	271
12	T14	15	6	26	16	6	6	16	96	187
13	T15	31	11	67	32	11	11	32	256	451
14	T16	81	23	189	87	23	23	87	957	1470
15	T17	31	6	34	32	6	6	32	320	467
16	T18	37	8	42	38	8	8	38	342	521
17	T19	19	4	12	20	4	4	20	140	223
18	T20	11	1	2	12	2	2	12	72	114
19	T21	3	1	8	4	2	2	4	28	52
20	T22	5	3	8	6	3	3	6	36	70
21	T23	5	3	6	6	3	3	6	28	60
22	T24	3	1	8	4	2	2	4	28	52
	TOTAL	642	129	610	668	131	131	668	6095	9087

^{*12&}lt;sup>th</sup> expression is not included due to missing right parenthesis

4.4 UTP & NFP Test Suite Size for Boolean Expressions

These test cases include Unique True Points and Near False Points. Test case generation aims at finding test cases that detect certain types of faults (illustrated in Section 4.1). The result is tabulated in Table 3. According to these results the number of test cases is increasing with the increase in number of variables in the expression, only exception are those expressions where variable are repeating in more than one term. Total number of test cases generated ranges from 9 to 2744.

Table 3: Size of Test Cases for TCAS 20 Boolean expressions

Expressio n	Number of Literal	UTP Test Cases	NFP TEST Cases	Total
T01	7	8	44	52
T02	9	16	129	145
T03	7	35	813	848
T04	5	15	19	34
T05	9	181	234	415
T06	11	10	94	104
T07	8	15	64	79
T08	8	4	32	36
T09	7	2	14	16
T10	13	12	120	132

T11	13	248	1592	1840
T13	12	1284	1460	2744
T14	7	33	81	114
T15	9	83	213	296
T16	12	750	1041	1791
T17	11	186	816	1002
T18	10	78	342	420
T19	8	24	120	144
T20	7	4	24	28
T21	3	3	6	9
T22	5	10	30	40
T23	3	4	8	12
T24	4	6	12	18

5. EXPERIMENTAL SETTINGS & RESULT

5.1 When Multiple Unique True Point (U) criteria is feasible for Boolean Expression

For the Boolean Expression (!a&b)|(c&d), MUTP criteria is feasible that is test suite includes the test cases which covers both values 0 and 1 for missing literals in both of the terms.

Table 4: All Test Cases for Boolean Expression (!(a&b)|(c&d)

Test Cases U followed by N		Test Cases N followed by U		
T1	0101	T5	1101	
T2	0110	Т6	0010	
Т3	0011	T1	0101	
T4	1111	T2	0110	
T5	1101	Т3	0011	
Т6	0010	T4	1111	

The comparison graph is drawn between APFD value of Boolean expression (!a&b)|(c&d) using UN order and NU order, which shows that value of APFD obtained using UN order is more than NU order.(See Figure 1 and 2)

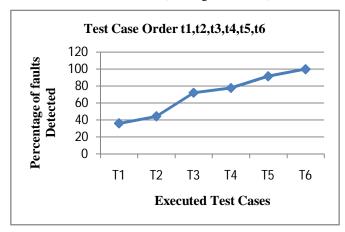


Figure 1: Graph for Boolean expression (! a&b)|(c&d) for UN ordered test cases with 62.01% APFD

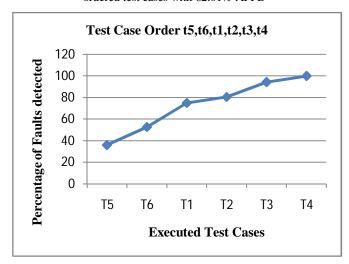


Figure 2: Graph for Boolean expression (! a&b)|(c&d) for NU ordered test cases with 45.8% APFD

5.2 When Multiple Unique True Point (U) criteria is infeasible for Boolean Expression

For the Boolean Expression (a&b)|(b&c) MUTP criteria is not feasible that is test suite does not include the test cases which covers both values 0 and 1 for missing literals in both of the terms.

Table 5: All Test Cases For Boolean expression (a&b)|(b&c)

Test Cases U followed by C		Test Cases C followed by U		
T1	110	Т3	010	
T2	011	T4	100	
T3	010	T5	001	
T4	100	T1	110	
T5	001	T2	011	

The comparison graph is drawn between APFD value of Boolean expression (!a&b)|(c&d) using UC order and CU order, which shows that value of APFD obtained using UC order is more than CU order(See Figure 3 and 4).

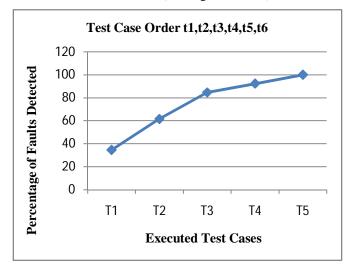


Figure 3: Graph for Boolean expression (!a&b)|(c&d) for UC ordered test cases with 67.86% APFD

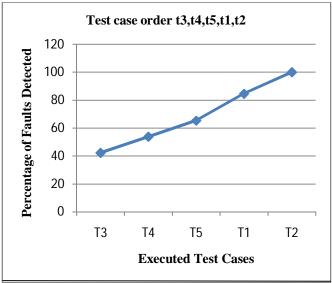


Figure 4: Graph for Boolean expression (! a&b)|(c&d) for CU ordered test cases with 59.29% APFD

Thus above experiment leads to some results which are listed in Table 6.

Table 6: Comparison of APFD for some Boolean expressions

S	Predicat	Feasibili	APFD(%) with		APFD(%)	
N	e	ty	Proposed		with Random	
•		Criteria	Approach		order	
1	(a&!b&d	MUTP	UC	67.63	CU	59.5
) (a&!c&	in	Order		Order	
	d) e)	-feasible				
2	(a&b) (a	MUTP	UC	57.10	CU	55.09
	&c) (b&c	in	Order		Order	
)	-feasible				
3	(a&b&c)	MUTP	UN	61.08	NU	56.01
	(d&e)	Feasible	Order		Order	
4	(a&b) (b	MUTP	UC	60	CU	55.89
	&!c) (!b	in	Order		Order	
	&c)	-feasible				
5	(!a&b)	MUTP	UN	62.01	NU	45.8
	(c&d)	Feasible	Order		Order	
6	(a&b) (b	MUTP	UC	67.86	CU	59.29
	&c)	in	Order		Order	
		-feasible				

6. CONCLUSION & FUTURE WORK

This paper illustrates the comparison between proposed algorithm and the random approach for Prioritization of Minimal MUMCUT test cases in order to improve regression testing. In proposed study the experiments were done on Boolean expressions where MUTP criteria is feasible and MUTP criteria is not feasible and provided higher value of Average Percentage of Faults Detected metric with MUTP (U) test cases followed by MNFP (N) i.e. UN order and MUTP (U) test cases followed by CUTPNFP(C) test cases i.e. UC order, as compared to the random order NU Order and CU order. In future the experiment need to be conducted on the Boolean expression having more no of literals and order of prioritization need to be validated for high rate of fault detection.

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